

The diagram illustrates the components and layout of a scanning electron microscope (SEM). The main column contains the electron gun (SO), condenser lens (BD), objective lens (IL), and eyepiece lens (AM). The intermediate lens (IN) and collector lens (CO) are located below the objective lens. The probe (PB) is positioned at the bottom of the column, just above the sample (MT). The sample is mounted on a stage (PW) with a detector (WT) and a deflector (IF). A coordinate system (X, Y, Z) is shown. Two insets are provided: one showing the sample area (MA) with markers M1 and M2, and another showing the sample area (W) with markers P1 and P2.

PRIOR ART

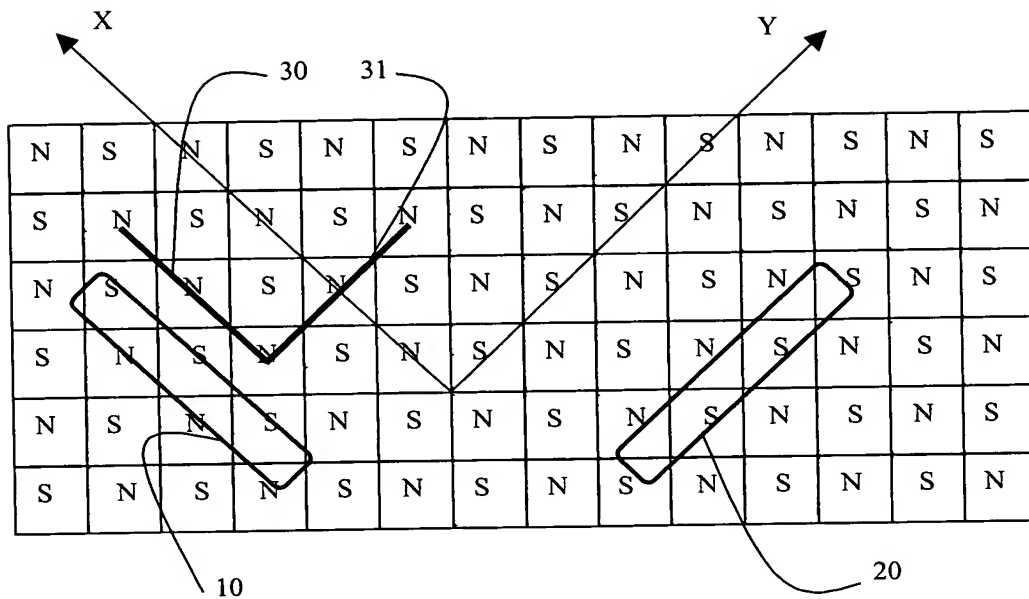


Fig. 2a

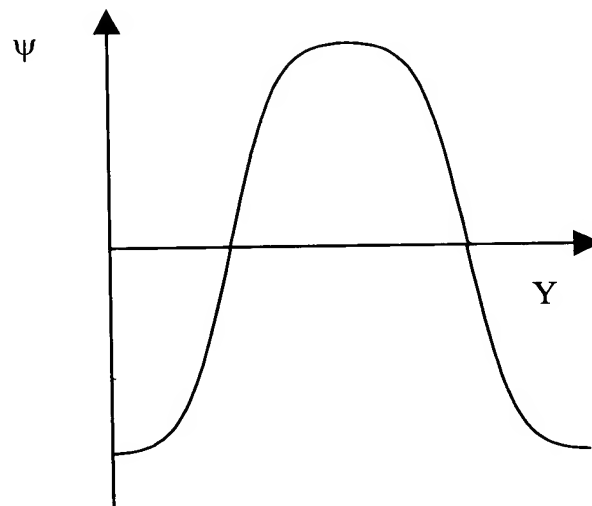


Fig. 2b

S	N	S	N	S	N	S
N	S	N	S	N	S	N
S	N	S	N	S	N	S
N	S	N	S	N	S	N
S	N	S	N	S	N	S
N	S	N	S	N	S	N

Fig. 2c

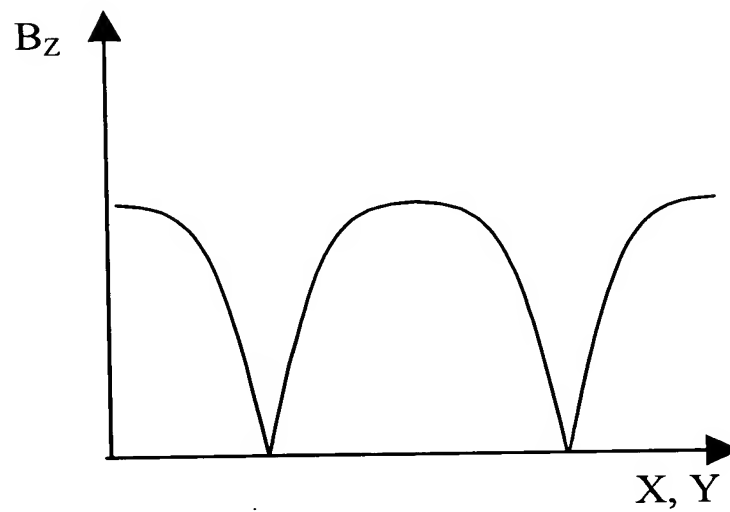


Fig. 2d

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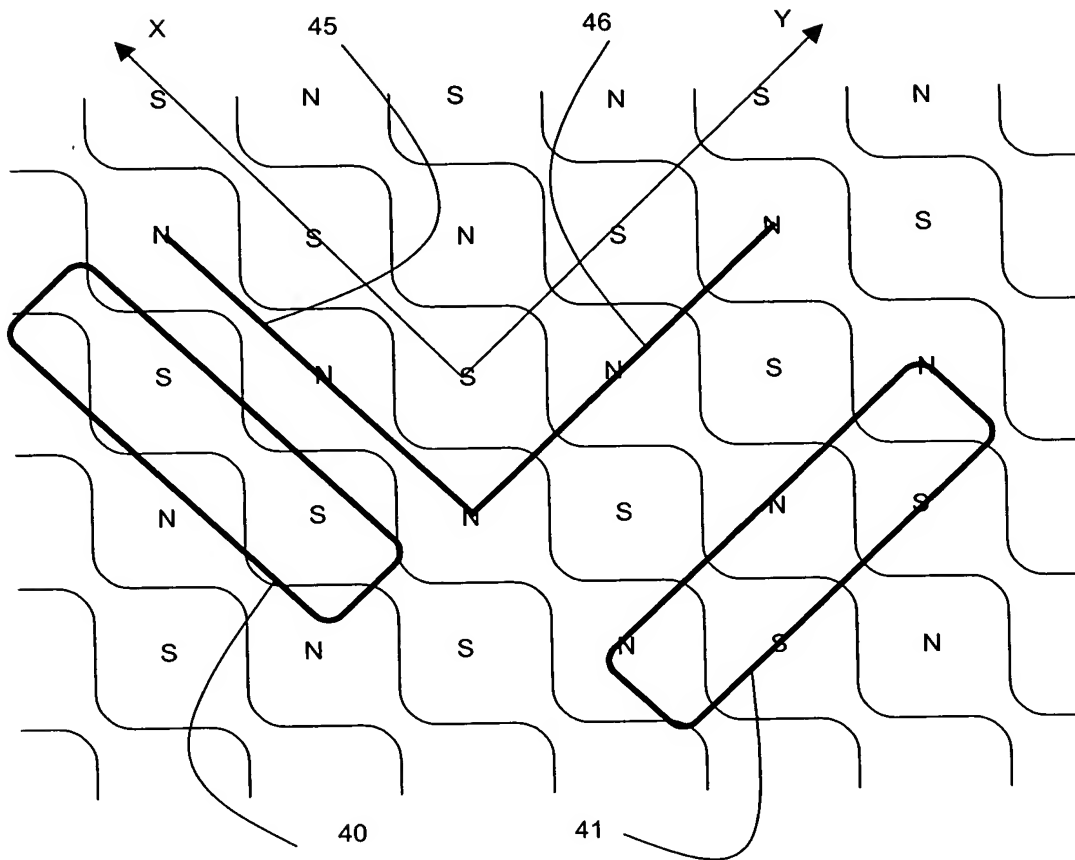


Fig. 3

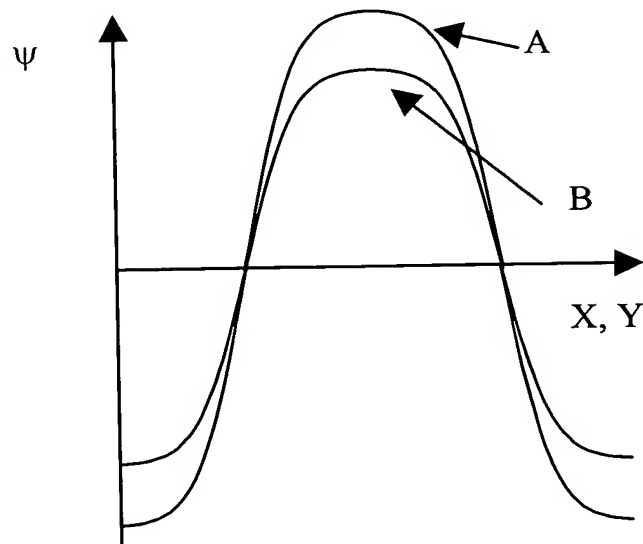


Fig. 4

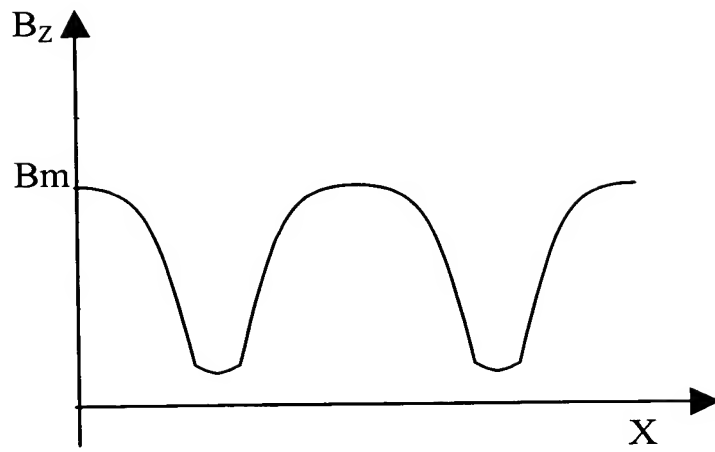


Fig. 5

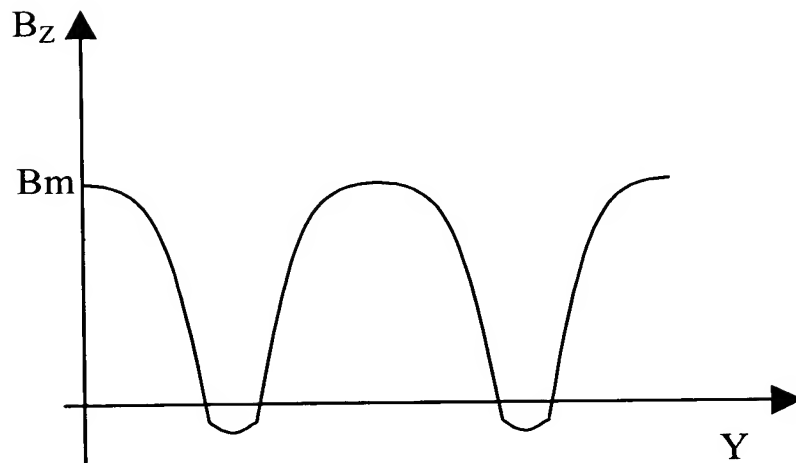


Fig. 6

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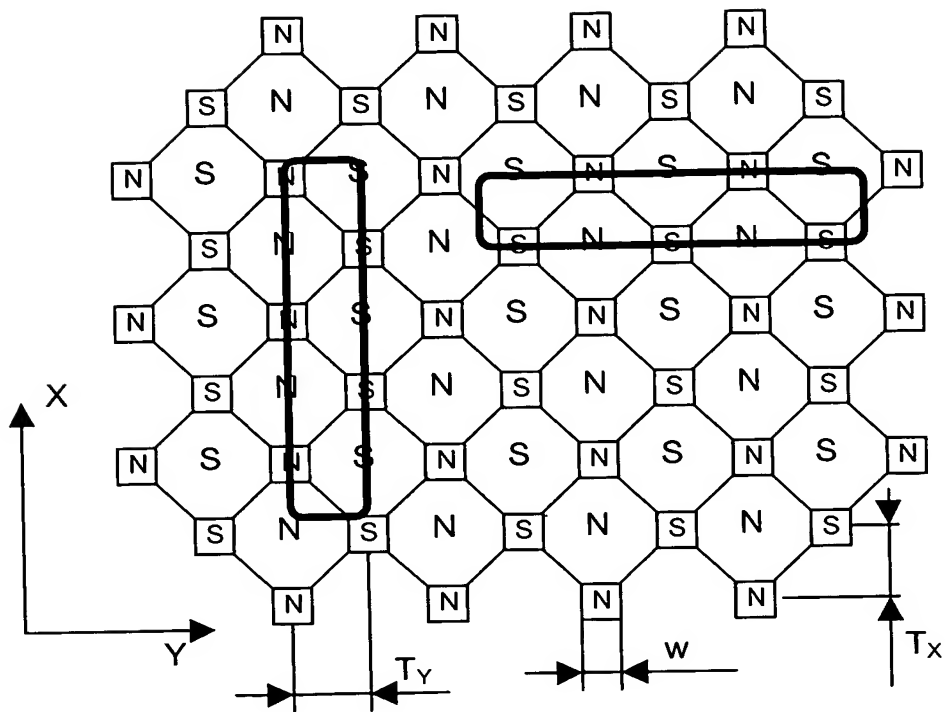


Fig. 7a

PRIOR ART

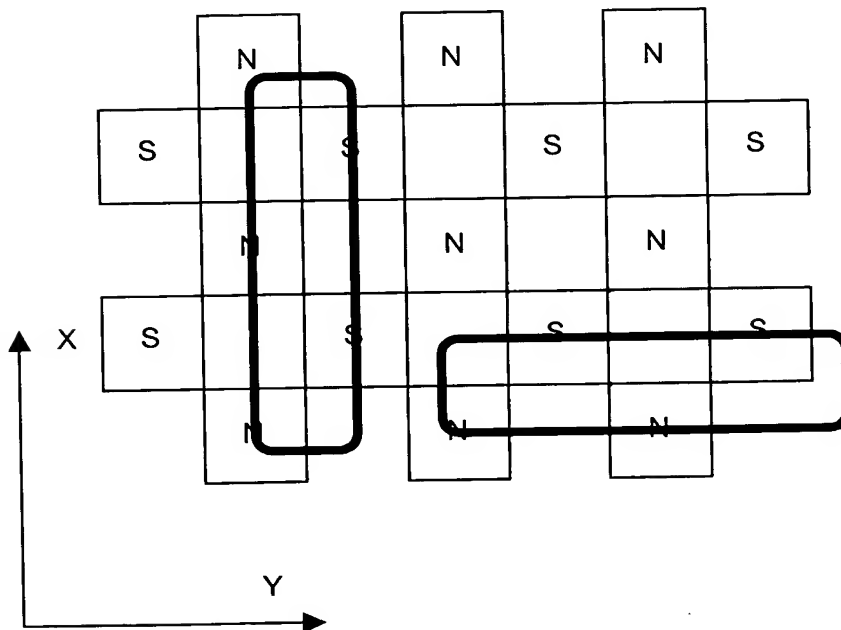


Fig. 7b

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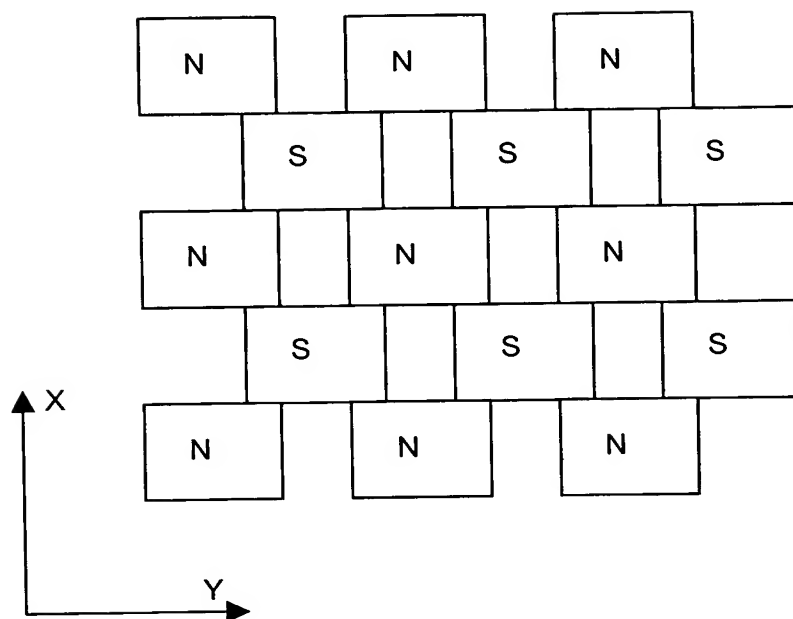


Fig. 7c

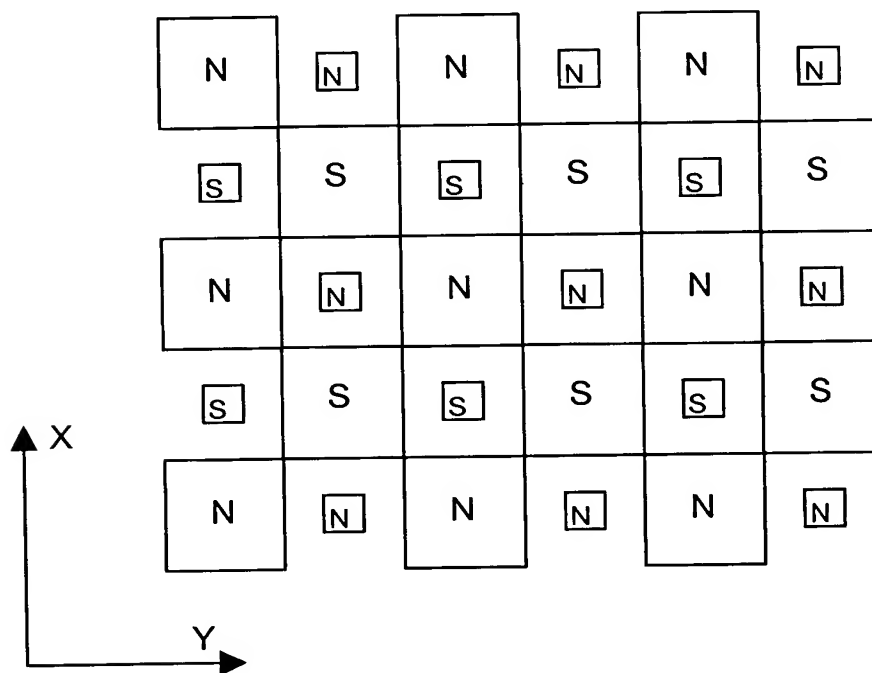


Fig. 7d

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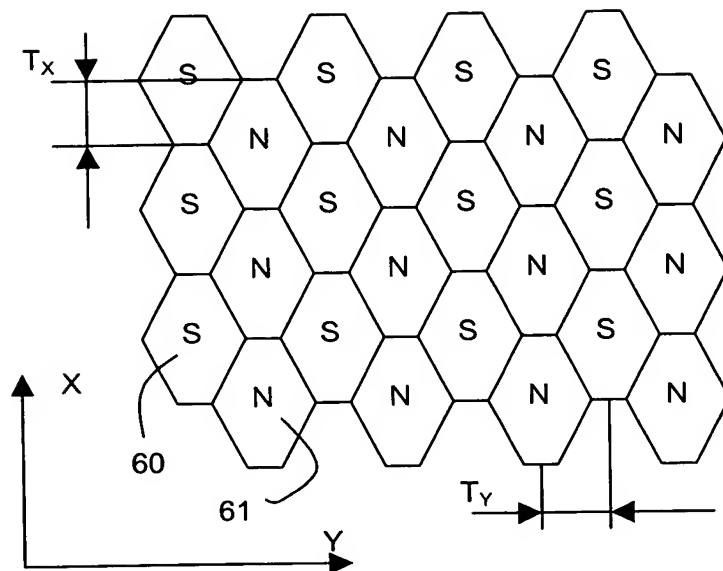


Fig. 8

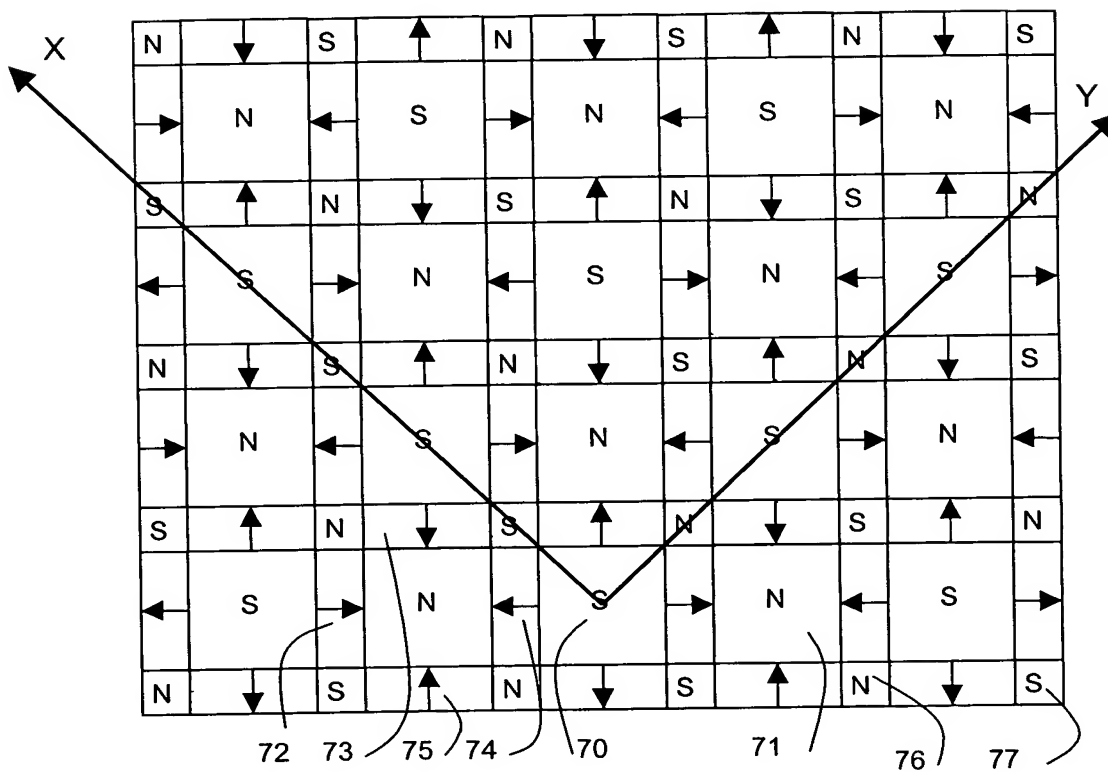


Fig. 9

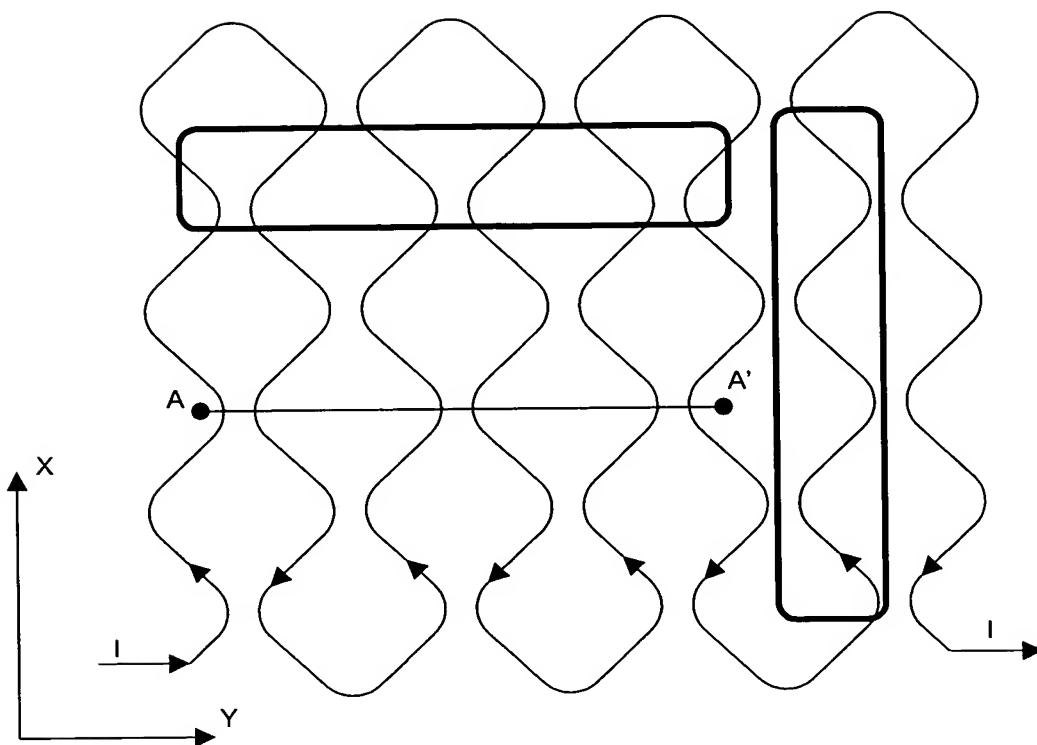


Fig. 10

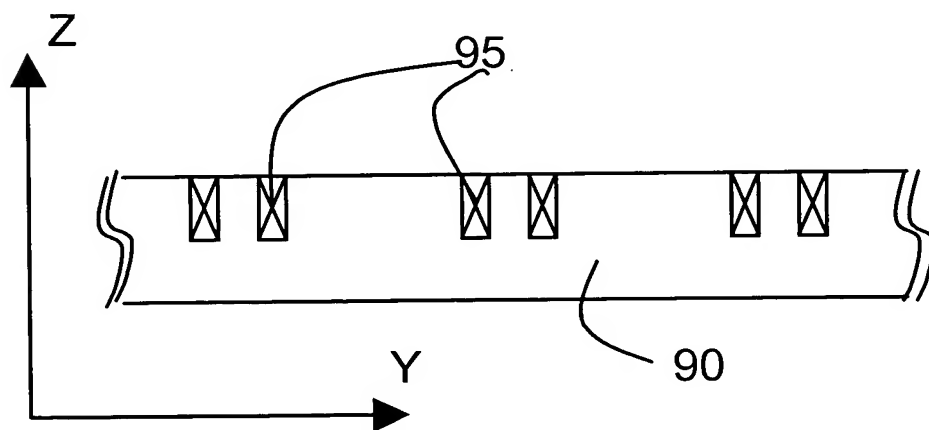


Fig. 11